

**Search Notes**

Application/Control No.

10/767,774

Examiner

Brian Young

Applicant(s)/Patent under  
Reexamination

MILLER, KEVIN LEE

Art Unit

2819

**SEARCHED**

Class	Subclass	Date	Examiner
341	143	2/28/2005	BY
	144		BY
	145		BY
	150		BY
	153		BY
	154		BY
	148		BY
	133		BY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
341	144	2/28/2005	BY
341	143	//	BY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST JPO,EPO, DERWENT, etc. NPL IEEE, PORTAL	2/28/2005	BY